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| Notice of References Cited | Application/Control No. 10/531,785 | Applicant(s)/Patent Under Reexamination MUCK ET AL. | |
| | Examiner Sai-Ming Chan | Art Unit 2616 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-------------------|----------------|
| * | A | US-2002/0048333 | 04-2002 | Ahmed et al. | 375/346 |
| * | B | US-6,369,758 | 04-2002 | Zhang, Deming | 342/383 |
| * | C | US-2002/0044524 | 04-2002 | Laroia et al. | 370/203 |
| * | D | US-2003/0072382 | 04-2003 | Raleigh et al. | 375/267 |
| * | E | US-5,193,115 | 03-1993 | Vobach, Arnold R. | 380/46 |
| * | F | US-5,495,432 | 02-1996 | Ho, Jyh-Chern | 708/313 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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